

5-bit multiplexed/1-bit latched 6-bit I²C-bus EEPROM DIP switch

Rev. 5.0 — 25 October 2021

Product data sheet

1 General description

PCA9559 is a 20-pin CMOS device consisting of one 6-bit non-volatile EEPROM registers, 5 hardware pin inputs and a 5-bit multiplexed output with one latched EEPROM bit. It is used for DIP switch-free or jumper-less system configuration and supports Mobile and Desktop VID Configuration, where 2 preset values (1 sets of internal non-volatile registers and 1 set of external hardware pins) set processor voltage for operation in either performance or deep sleep modes. The PCA9559 is also useful in server and telecom/networking applications when used to replace DIP switches or jumpers, since the settings can be easily changed via I²C/SMBus without having to power down the equipment to open the cabinet. The non-volatile memory retains the most current setting selected before the power is turned off.

The PCA9559 typically resides between the CPU and Voltage Regulator Module (VRM) when used for CPU VID (Voltage IDentification code) configuration. It is used to bypass the CPU-defined VID values and provide a different set of VID values to the VRM, if an increase in the CPU voltage is desired. An increase in CPU voltage combined with an increase in CPU frequency leads to a performance boost of up to 7.5%. Lower CPU voltage reduces power consumption.

The PCA9559 has 2 address pins allowing up to 4 devices to be placed on the same I²C-bus or SMBus.

2 Features and benefits

- 5-bit 2-to-1 multiplexer, 1-bit latch DIP switch
- 6-bit internal non-volatile register
- Internal non-volatile register programmable and readable via I²C-bus
- Override input forces all outputs to logic 0
- 5 open drain multiplexed outputs
- 1 open drain non-multiplexed (latched) output
- 5 V and 2.5 V tolerant inputs/outputs
- Useful for 'jumperless' configuration of PC motherboards
- 2 address pins, allowing up to 4 devices on the I²C-bus
- ESD protection exceeds 2000 V HBM per JESD22-A114 and 1000 V CDM per JESD22-C101
- Latch-up testing is done to JESDEC Standard JESD78 which exceeds 100 mA.



3 Ordering information

| Table 1. Orderin | Table 1. Ordering information | | | | | | |
|------------------|-------------------------------|---------|--|----------|--|--|--|
| Type number | Topside | Package | | | | | |
| | marking | Name | Description | Version | | | |
| PCA9559PW | PCA9559 | TSSOP20 | plastic thin shrink small outline package; 20 leads; body width 4.4 mm | SOT360-1 | | | |

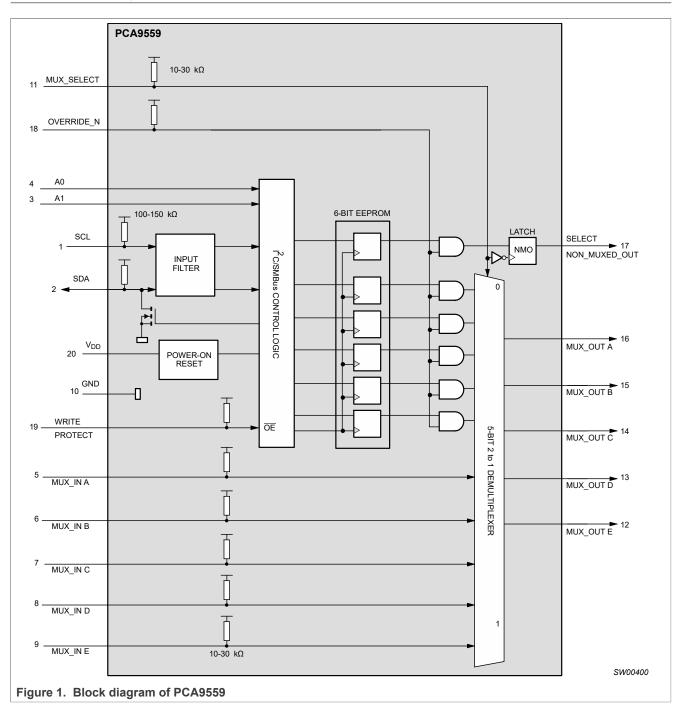
3.1 Ordering options

Table 2. Ordering options

| Type number | Orderable part number | Package | Packing method ^[1] | Minimum order quantity | Temperature |
|-------------|--------------------------|---------|-------------------------------|---------------------------|------------------------------|
| PCA9559PW | PCA9559PW,118 | TSSOP20 | REEL 13" Q1 NDP | 2500 | T_{amb} = -40 °C to +85 °C |

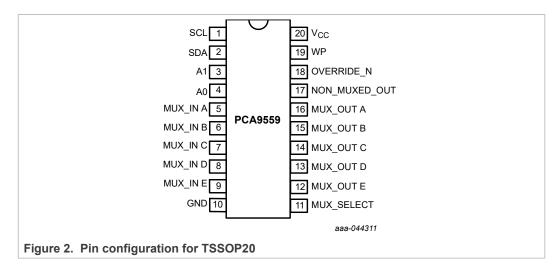
[1] Standard packing quantities and other packaging data are available at <u>www.nxp.com/packages/</u>.

4 Block diagram



5 Pinning information

5.1 Pinning



5.2 Pin description

| Table 3. Pin descrip | tion | |
|----------------------|------|--|
| Symbol | Pin | Description |
| SCL | 1 | serial I ² C-bus clock line |
| SDA | 2 | serial bidirectional I ² C-bus data line |
| A1 | 3 | address 1 |
| A0 | 4 | address 0 |
| MUX_IN_A | 5 | external input A to multiplexer |
| MUX_IN_B | 6 | external input B to multiplexer |
| MUX_IN_C | 7 | external input C to multiplexer |
| MUX_IN_D | 8 | external input D to multiplexer |
| MUX_IN_E | 9 | external input E to multiplexer |
| GND | 10 | ground |
| MUX_SELECT | 11 | selects MUX_IN inputs or register contents for MUX_OUT outputs |
| MUX_OUT_E | 12 | open-drain multiplexed output E |
| MUX_OUT_D | 13 | open-drain multiplexed output D |
| MUX_OUT_C | 14 | open-drain multiplexed output C |
| MUX_OUT_B | 15 | open-drain multiplexed output B |
| MUX_OUT_A | 16 | open-drain multiplexed output A |
| NON-MUXED_OUT | 17 | open-drain output from non-volatile memory |
| OVERRIDE_N | 18 | forces all outputs to logic 0 |
| WP | 19 | non-volatile register write-protect |
| V _{CC} | 20 | supply voltage (3.0 V to 3.6 V) |

6 Functional description

When the MUX_SELECT signal is logic 0, the multiplexer will select the data from the non-volatile register to drive on the MUX_OUT pins. When the MUX_SELECT signal is logic 1, the multiplexer will select the MUX_IN lines to drive on the MUX_OUT pins. The MUX_SELECT signal is also used to latch the NON_MUXED_OUT signal which outputs data from the non-volatile register. The NON_MUXED_OUT signal latch is transparent when MUX_SELECT is in a logic 0 state, and will latch data when MUX_SELECT is in a logic 1 state. When the active-LOW OVERRIDE_N signal is set to logic 0 and the MUX_SELECT signal is at a logic 0, all outputs will be driven to logic 0. This information is summarized in Table 4.

The Write Protect (WP) input is used to control the ability to write the contents of the 6bit non-volatile register. If the WP signal is logic 0, the I^2 C-bus will be able to write the contents of the non-volatile register. If the WP signal is logic 1, data will not be allowed to be written into the non-volatile register.

The factory default for the contents of the non-volatile register are all logic 0. These stored values can be read or written using the I^2 C-bus (described in <u>Section 6.1</u>).

The OVERRIDE_N, WP, MUX_IN, and MUX_SELECT signals have internal pull-up resistors. See <u>Section 11</u> and <u>Section 10</u> for hysteresis and signal spike suppression figures.

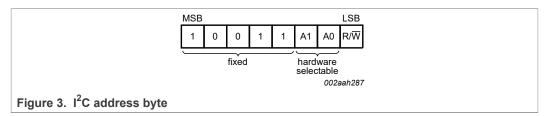
| OVERRIDE_N | MUX_SELECT | MUX_OUT OUTPUTS | NON_MUXED_OUT OUTPUT |
|------------|------------|-------------------------------|--|
| 0 | 0 | All 0s | All 0s |
| 0 | 1 | MUX_IN inputs | latched NON- MUXED_OUT ^[1] |
| 1 | 0 | From non-volatile register | From non-volatile register |
| 1 | 1 | MUX_IN inputs | From non-volatile register |

Table 4. Function table

[1] NON_MUXED_OUT state will be the value present on the output at the time of the MUX_SELECT input transitioned from a logic 0 to a logic 1 state.

6.1 I²C-bus interface

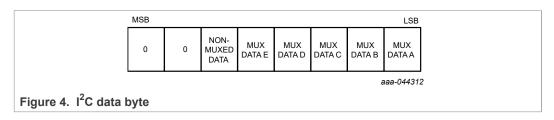
Communicating with this device is initiated by sending a valid address on the I²C-bus. The address format has 5 fixed bits and two user-programmable bits followed by a 1-bit read/write value which determines the direction of the data transfer.



Following the address and acknowledge bit are 8 data bits which, depending on the read/ write bit in the address, will read data from or write data to the non-volatile register. Data will be written to the register if the read/write bit is logic 0 and the WP input is logic 0.

Data will be read from the register if the bit is logic 1. The four high-order bits are latched outputs, while the four low order bits are multiplexed outputs (Figure 4).

NOTE: To ensure data integrity, the non-volatile register must be internally write protected when V_{CC} to the l²C-bus is powered down or VCC to the component is dropped below normal operating levels.



6.2 Power-on reset

When power is applied to V_{CC}, an internal Power-On Reset (POR) holds the PCA9559 in a reset state until V_{CC} has reached V_{POR}. At that point, the reset condition is released and the PCA9559 volatile registers and I²C/SMBus state machine will initialize to their default states.

The MUX_OUT and NON_MUXED_OUT pin values depend on:

- The OVERRIDE # and MUX_SELECT logic levels
- The previously stored values in the EEPROM registers/current MUX_IN pin values as shown in <u>Table 1</u>.

7 Limiting values

Table 5. Limiting values [1] [2]

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

| Symbol | Parameter | Conditions | Min | Max | Unit |
|------------------|---------------------|------------|------|-----------------------|------|
| V _{CC} | supply voltage | | -0.5 | +4.6 | V |
| VI | input voltage | [3] | -1.5 | V _{CC} + 1.5 | V |
| Vo | output voltage | [3] | -0.5 | V _{CC} + 1.5 | V |
| T _{stg} | storage temperature | | -60 | +150 | °C |

[1] Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

[2] The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150 °C.

[3] The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

[3] The input and output voltage ratings may be exceeded if the input and output current ratings are o

8 Recommended operating conditions

Table 6. Operating conditions

| Symbol | Parameter | Conditions | Min | Мах | Unit |
|-----------------|-------------------------|----------------------------------|------|------|------|
| V _{CC} | supply voltage | | 3.0 | 3.6 | V |
| V _{IL} | LOW-level input voltage | SCL, SDA; I _{OL} = 3 mA | -0.5 | +0.9 | V |

 Table 6. Operating conditions...continued

| Symbol | Parameter | Conditions | Min | Max | Unit |
|------------------|-------------------------------------|-----------------------------------|------|------|------|
| V _{IH} | HIGH-level input voltage | SCL, SDA; I _{OL} = 3 mA | 2.7 | 4.0 | V |
| V _{OL} | LOW-level output voltage | SCL, SDA | | | |
| | | I _{OL} = 3 mA | - | 0.4 | V |
| | | I _{OL} = 6 mA | - | 0.6 | V |
| V _{IL} | LOW-level input voltage | OVERRIDE_N, MUX_IN, MUX_SELECT | -0.5 | +0.8 | V |
| V _{IH} | HIGH-level input voltage | OVERRIDE_N, MUX_IN, MUX_SELECT | 2.0 | 4.0 | V |
| I _{OL} | LOW-level output current | MUX_OUT, NON_MUXED_ OUT | - | 8 | mA |
| I _{ОН} | HIGH-level output current | MUX_OUT, NON_MUXED_ OUT | - | 100 | μA |
| Δt/ΔV | input transition rise and fall rate | | 0 | 10 | ns/V |
| T _{amb} | ambient temperature | | 0 | 70 | °C |

9 Thermal characteristics

Table 7. Thermal characteristics

| Symbol | Parameter | Conditions | Тур | Unit |
|----------------------|---|-----------------|-----|------|
| R _{th(j-a)} | thermal resistance from junction to ambient | TSSOP20 package | 146 | °C/W |

10 Static characteristics

Table 8. Static characteristics

 $V_{\mbox{\scriptsize HYS}}$ is the hysteresis of Schmitt-Trigger inputs

| Symbol | Parameter | Conditions | Min | Тур | Max | Unit |
|------------------|----------------------------------|--|------|-----|-----------------------|------|
| Supply | | | I | | | |
| V _{CC} | supply voltage | | 3 | - | 3.8 | V |
| I _{DD} | supply current | operating mode | | | | |
| | | all inputs = 0 V | - | - | 10 | mA |
| | | all inputs = V _{CC} | - | - | 600 | μA |
| V _{POR} | power-on reset voltage | no load; V _I = V _{CC} or GND | - | 1.9 | 2.6 | V |
| Input SC | L; input/output SDA | | l | 1 | | |
| V _{IL} | LOW-level input voltage | | -0.5 | - | +0.8 | V |
| V _{IH} | HIGH-level input voltage | | 2 | - | V _{CC} = 0.5 | V |
| I _{OL} | LOW-level output current | V _{OL} = 0.4 V | 3 | - | - | mA |
| | | V _{OL} = 0.6 V | 6 | - | - | mA |
| | HIGH-level input leakage current | V _I = V _{CC} | -1.5 | - | -12 | μA |
| I _{LIH} | | | | | | |

Table 8. Static characteristics...continued

V_{HYS} is the hysteresis of Schmitt-Trigger inputs

| Symbol | Parameter | Conditions | Min | Тур | Мах | Unit |
|------------------|----------------------------------|----------------------------------|--------|-----|-------|------|
| C _i | input capacitance | | - | - | 10 | pF |
| OVERRID | E_N, WP, MUX_SELECT | | | | | |
| I _{LIH} | HIGH-level input leakage current | V _I = V _{CC} | -20 | - | -100 | μA |
| ILIL | LOW-level input leakage current | V _I = GND | -86 | - | -267 | μA |
| C _i | input capacitance | | - | - | 10 | pF |
| MUX_IN_A | A, MUX_IN_B, MUX_IN_C, MUX_IN_I | , MUX_IN_E | | | | |
| I _{LIH} | HIGH-level input leakage current | $V_{I} = V_{CC}$ | -0.166 | - | -0.75 | mA |
| ILIL | LOW-level input leakage current | V _I = GND | -0.72 | - | -2 | mA |
| Ci | input capacitance | | - | | 10 | pF |
| Inputs A0 | , A1 | | | | I | |
| I _{LIH} | HIGH-level input leakage current | $V_{I} = V_{CC}$ | -1 | - | +1 | μA |
| IIL | LOW-level input current | V _I = GND | -1 | - | +1 | μA |
| C _i | input capacitance | | - | - | 10 | pF |
| MUX_OUT | ΓE⇒A | , | , I | | , | |
| V _{OL} | LOW-level output voltage | I _{OL} = 100 μA | - | - | 0.4 | V |
| | | I _{OL} = 2 mA | - | - | 0.7 | V |
| NON-MUX | COUT | | II | | 1 |] |
| V _{OL} | LOW-level output voltage | I _{OL} = 100 μA | - | - | 0.4 | V |
| | | I _{OL} = 2 mA | - | - | 0.7 | V |

11 Dynamic characteristics

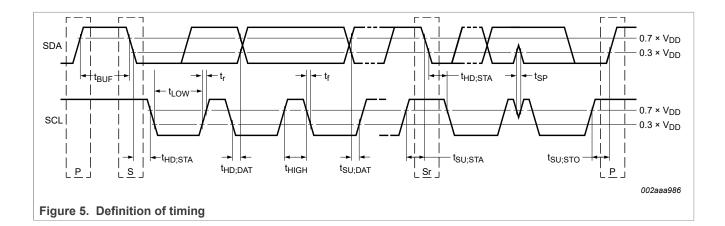
Table 9. Dynamic characteristics

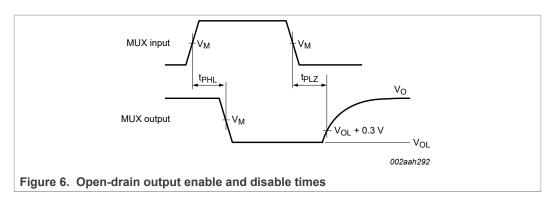
| Symbol | Parameter | Conditions | Min | Тур | Мах | Unit |
|------------------|-------------------------------|------------|-----|-----|-----|------|
| MUX_IN = | MUX_OUT | 1 | | I | | |
| t _{PLH} | LOW to HIGH propagation delay | | - | 28 | 37 | ns |
| t _{PHL} | HIGH to LOW propagation delay | | - | 16 | 21 | ns |
| Select ⇒ | MUX_OUT | | 1 1 | I | 1 | |
| t _{PLH} | LOW to HIGH propagation delay | | - | 30 | 39 | ns |
| t _{PHL} | HIGH to LOW propagation delay | | - | 17 | 22 | ns |
| OVERRID | E_N ⇒ NON-MUX_OUT | | 1 1 | l | l | |
| t _{PLH} | LOW to HIGH propagation delay | | - | 34 | 43 | ns |
| t _{PHL} | HIGH to LOW propagation delay | | - | 19 | 25 | ns |
| OVERRID | E_N ⇒ MUX_OUT | | | | 1 | |
| t _{PLH} | LOW to HIGH propagation delay | | - | 31 | 41 | ns |
| t _{PHL} | HIGH to LOW propagation delay | | - | 21 | 27 | ns |

| Symbol | Parameter | Conditions | Min | Тур | Мах | Unit |
|----------------------|--|---|-----|-----|------|------|
| t _r | rise time | output | 1.0 | - | 3 | ns/V |
| t _f | fall time | output | 1.0 | - | 3 | ns/V |
| P _F | Pull-up resistor for outputs | | 1.0 | - | - | ns/V |
| CL | load capacitance | test load on outputs | - | - | - | pF |
| l ² C-bus | | | | | | |
| f _{SCL} | SCL clock frequency | | 10 | - | 400 | kHz |
| t _{BUF} | bus free time between a STOP and START condition | | 1.3 | - | - | μs |
| t _{hd;sta} | hold time (repeated) START condition | After this period, the first clock pulse is generated | 600 | - | - | ns |
| t _{LOW} | LOW period of the SCL clock | | 1.3 | - | - | μs |
| t _{HIGH} | HIGH period of the SCL clock | | 600 | - | -12 | ns |
| t _{SU;STA} | set-up time for a repeated START condition | | 600 | - | -32 | ns |
| t _{HD;DAT} | data hold time | | 0 | - | 10 | ns |
| t _{SU;DAT} | data set-up time | | 100 | - | -100 | ns |
| t _{SP} | pulse width of spikes that must be suppressed by the input filters | | 0 | - | 50 | ns |
| t _{su;sto} | set-up time for STOP condition | | 600 | - | 10 | ns |
| t _r | rise time of both SDA and SCL signals | 10 - 400 pF bus | 20 | - | 300 | ns |
| t _f | fall time of both SDA and SCL signals | 10 - 400 pF bus | 20 | - | 300 | ns |
| CL | load capacitance | for each bus line | - | - | 400 | pF |
| t _W | write cycle time ^[1] | | - | 15 | - | ms |

 Table 9. Dynamic characteristics...continued

[1] WRITE CYCLE time can only be measured indirectly during the write cycle. During this time, the device will not acknowledge its I²C Address.





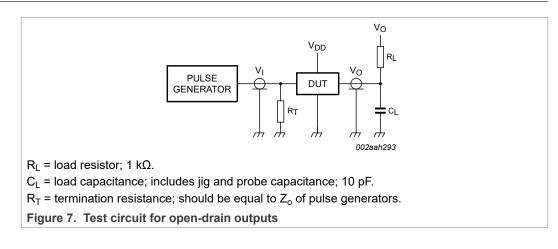
12 Non-volatile storage specifications

 Table 10. Non-volatile storage specifications

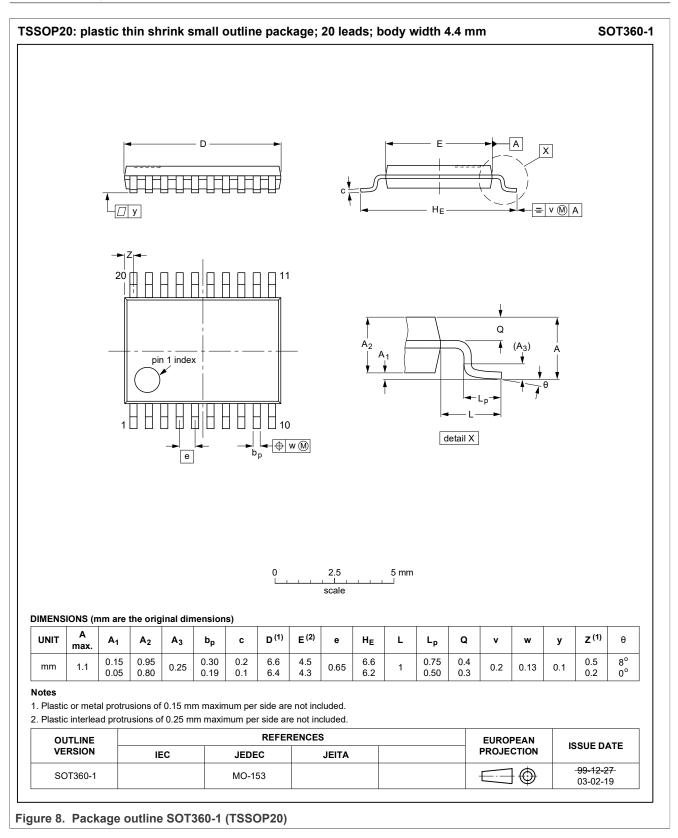
| Parameter | Specification |
|------------------------------------|--------------------------|
| memory cell data retention | 10 years (minimum) |
| number of memory cell write cycles | 100,000 cycles (minimum) |

Application note AN250, " I^2C DIP Switch" provides additional information on memory cell data retention and the minimum number of write cycles.

13 Test information



14 Package outline



PCA9559 Product data sheet

15 Soldering of SMD packages

This text provides a very brief insight into a complex technology. A more in-depth account of soldering ICs can be found in Application Note *AN10365 "Surface mount reflow soldering description"*.

15.1 Introduction to soldering

Soldering is one of the most common methods through which packages are attached to Printed Circuit Boards (PCBs), to form electrical circuits. The soldered joint provides both the mechanical and the electrical connection. There is no single soldering method that is ideal for all IC packages. Wave soldering is often preferred when through-hole and Surface Mount Devices (SMDs) are mixed on one printed wiring board; however, it is not suitable for fine pitch SMDs. Reflow soldering is ideal for the small pitches and high densities that come with increased miniaturization.

15.2 Wave and reflow soldering

Wave soldering is a joining technology in which the joints are made by solder coming from a standing wave of liquid solder. The wave soldering process is suitable for the following:

- Through-hole components
- Leaded or leadless SMDs, which are glued to the surface of the printed circuit board

Not all SMDs can be wave soldered. Packages with solder balls, and some leadless packages which have solder lands underneath the body, cannot be wave soldered. Also, leaded SMDs with leads having a pitch smaller than ~0.6 mm cannot be wave soldered, due to an increased probability of bridging.

The reflow soldering process involves applying solder paste to a board, followed by component placement and exposure to a temperature profile. Leaded packages, packages with solder balls, and leadless packages are all reflow solderable.

Key characteristics in both wave and reflow soldering are:

- Board specifications, including the board finish, solder masks and vias
- Package footprints, including solder thieves and orientation
- The moisture sensitivity level of the packages
- Package placement
- Inspection and repair
- Lead-free soldering versus SnPb soldering

15.3 Wave soldering

Key characteristics in wave soldering are:

- Process issues, such as application of adhesive and flux, clinching of leads, board transport, the solder wave parameters, and the time during which components are exposed to the wave
- · Solder bath specifications, including temperature and impurities

15.4 Reflow soldering

Key characteristics in reflow soldering are:

- Lead-free versus SnPb soldering; note that a lead-free reflow process usually leads to higher minimum peak temperatures (see <u>Figure 9</u>) than a SnPb process, thus reducing the process window
- Solder paste printing issues including smearing, release, and adjusting the process window for a mix of large and small components on one board
- Reflow temperature profile; this profile includes preheat, reflow (in which the board is heated to the peak temperature) and cooling down. It is imperative that the peak temperature is high enough for the solder to make reliable solder joints (a solder paste characteristic). In addition, the peak temperature must be low enough that the packages and/or boards are not damaged. The peak temperature of the package depends on package thickness and volume and is classified in accordance with Table 11 and Table 12

Table 11. SnPb eutectic process (from J-STD-020D)

| Package thickness (mm) | Package reflow temperature (°C) | | |
|------------------------|---------------------------------|-------|--|
| | Volume (mm ³) | | |
| | < 350 | ≥ 350 | |
| < 2.5 | 235 | 220 | |
| ≥ 2.5 | 220 | 220 | |

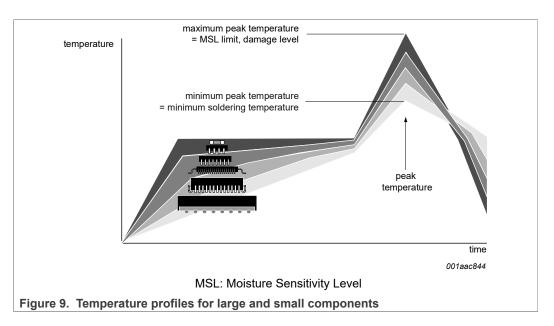
Table 12. Lead-free process (from J-STD-020D)

| Package thickness (mm) | Package reflow temperature (°C) | | | |
|------------------------|---------------------------------|-------------|--------|--|
| | Volume (mm ³) | | | |
| | < 350 | 350 to 2000 | > 2000 | |
| < 1.6 | 260 | 260 | 260 | |
| 1.6 to 2.5 | 260 | 250 | 245 | |
| > 2.5 | 250 | 245 | 245 | |

Moisture sensitivity precautions, as indicated on the packing, must be respected at all times.

Studies have shown that small packages reach higher temperatures during reflow soldering, see <u>Figure 9</u>.

5-bit multiplexed/1-bit latched 6-bit I²C-bus EEPROM DIP switch



For further information on temperature profiles, refer to Application Note *AN10365 "Surface mount reflow soldering description"*.

16 Soldering: PCB footprints

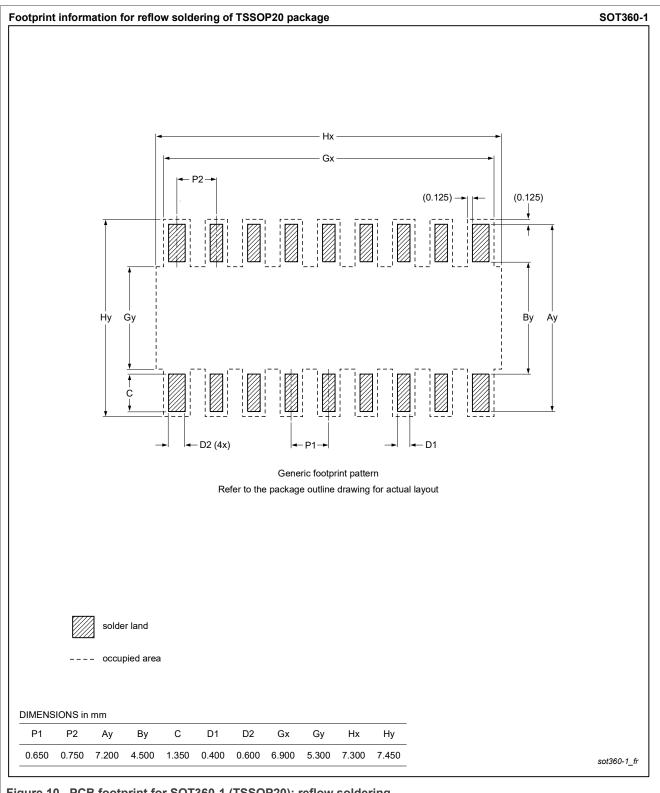


Figure 10. PCB footprint for SOT360-1 (TSSOP20); reflow soldering

17 Abbreviations

| Table 13. Abbreviations | | | |
|-------------------------|---|--|--|
| Acronym | Description | | |
| CDM | Charged-Device Model | | |
| CMOS | Complementary Metal-Oxide Semiconductor | | |
| CPU | Central Processing Unit | | |
| DIP | Dual In-line Package | | |
| EEPROM | Electrically Erasable Programmable Read-Only Memory | | |
| ESD | ElectroStatic Discharge | | |
| НВМ | Human Body Model | | |
| I ² C-bus | Inter-Integrated Circuit bus | | |
| PCB | Printed-Circuit Board | | |
| SMBus | System Management Bus | | |
| VID | Voltage IDentification code | | |
| VRM | Voltage Regulator Module | | |

18 Revision history

Table 14. Revision history

| Document ID | Release date | Data sheet status | Change notice | Supersedes |
|----------------|---|---|---------------|-------------|
| PCA9559 v.5 | 20211025 | Product data sheet | - | PCA9559 v.4 |
| Modifications: | NXP Semicondu • <u>Section 2</u> : MM is | The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors. <u>Section 2</u>: MM is removed from data sheet during update as no longer required. Removed PCA9959PW,112; tube pack method was discontinued DN86 July 2017. | | |
| PCA9559 v.4 | 20030627 | Product data sheet | - | PCA9559 v.3 |

19 Legal information

19.1 Data sheet status

| Document status ^{[1][2]} | Product status ^[3] | Definition |
|-----------------------------------|-------------------------------|---|
| Objective [short] data sheet | Development | This document contains data from the objective specification for product development. |
| Preliminary [short] data sheet | Qualification | This document contains data from the preliminary specification. |
| Product [short] data sheet | Production | This document contains the product specification. |

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <u>http://www.nxp.com</u>.

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